
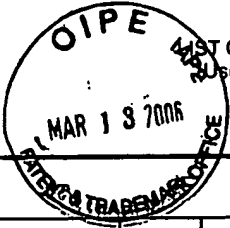


Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. H0004116-US		SERIAL NO. 10/614,807	
 <p>LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)</p>					APPLICANT Wuwen Yi et al.			
					FILING DATE July 9, 2003		GROUP 1742	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
HW	AA	2002/0041819 A1	04/02	Kumar et al.				
	AB							
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	AD							
	AE							
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		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AF							
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	AH							
	AI							
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HW	AK	V. Pavate et al., <i>Correlation between Aluminum alloy sputtering target metallurgical characteristics, Arc initiation, and in-film defect density</i> , pp. 42-47, SPIE Vol. 3214, 1997						
	AL							
EXAMINER /Harry Wilkins/		DATE CONSIDERED 04/24/2006						
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<div style="text-align: center;">  </div>				LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)			
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*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
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FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AH						
	AI						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
HW	AJ	C.A. Michaluk, et al. <i>Methodologies for Determining the Global Texture of Tantalum Plate Using X-Ray Diffraction</i> , The Minerals, Metals & Materials Society, pps. 123-131, 1996.					
	AK						
EXAMINER /Harry Wilkins/		DATE CONSIDERED 04/24/2006					
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